## Fast Kickers at DESY

- Injection / ejection in a TESLA like DR
- Generation of a pulse with a pulse length of $12 n s$
- Measurement at TTF 2
- Full power test
- Measurements at ATF
- XFEL activity

Talk given by Hans Weise
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## TESLA like damping ring- injection / ejection



## Generation of pulse with a pulse length of 12 ns



- principle set up of the pulser
- Behlke switch built in Mosfet technology
- max. 1000 single pulses with $1 \mu$ s spacing



## Behlke switch data:

| Type | HTS 80-12UF |
| :--- | :--- |
| Pulse voltage | 8 kV |
| Pulse current | 120 A (tp<50ns) |
| Jitter | 100 ps |
| Rise time (10-90\%) | 2 ns |

## Pulser data:

| Voltage | 6.5 kV |
| :--- | :--- |
| Pulse current | 73.6 A |
| Frequency (burst) | 1 MHz |
| Number of pulses | 1000 |
| Pulse length | 12 ns |

## Ripple Measurement




## Timing Jitter

Swicht HTS 80-12UF $\mathrm{t}_{\mathrm{on}}=10 \mathrm{~ns}$


Channel 1 Trigger (Delay .-Trigger generator) Channel 4 Pulse current with a Jitter of 200ps (Behlke Data: Typical Turn-on Jitter of 100ps)


| Pearson Current Monitor Model 6585 |  |
| :--- | :--- |
| Sensitivity | $1 \mathrm{~V} / \mathrm{A}+/-1 \%$ |
|  | $0.5 \mathrm{~V} / \mathrm{A}$ into |
| $50 \Omega$ |  |
| Output resistance | $50 \Omega$ |
| Max. peak current | 500 A |
| Max. rms current | 10 A |
| Droop rate | $0.8 \% / \mathrm{ss}$ |
| Useable rise time | 1.5 ns |
| Low frequency 3 dB cut-off | 400 Hz |
| High frequency $+/-3 \mathrm{~dB}$ | 250 MHz |

## Measurements at TTF 2



Ceramic Kicker

| Data: |  |
| :--- | :--- |
| Voltage | 7.0 kV |
| Pulse current | 61 A |
| Pulse length | 12 ns |



- principle set up of the kicker
- measure the kicker strength
- scan the kicker pulse with a step width of 0.5 ns and taking 20 pulses for each data point.



## Measurements at TTF 2



Measurement on kicker 'flat' top to investigate influence of timing jitter. Standard deviations of unkicked / kicked bunch (eposx1/eposx2) are given below as well as relative error. Smallest error as low as $0.5 \%$ at certain delay, relative error increases with distance from 'flat, top. Kicker HV = 7kV.


## Pulse with a burst frequency of 3MHz



- max. 1000 single pulses with $1 \mu \mathrm{~s}$ spacing

| Pulser data: |  |
| :--- | :--- |
| Voltage | 6.5 kV |
| Pulse current | 73.6 A |
| Frequency (burst) | 3 MHz |
| Number of pulses | 3000 |
| Pulse length | 12 ns |

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## Full power test with a HTS 50-08-UF switch

For this Measurement we have a pulser with three switches HTS 50-08 UF. Full power test with three Switches 500 single pulses and $1 \mu$ s spacing each.

| Voltages | 4.5 kV |
| :--- | :--- |
| Current | 38 A |
| Pulse length | 8 ns |
| Rise time (10-90\%) | 3 ns |
| Micro pulse repetition rate | 3 MHz |
| Macro pulse repetition rate | 1 Hz |
| Number of pulse | 1500 |




| Time | Temperature <br> Power Stack $\left[{ }^{\circ} \mathrm{C}\right]$ | Temperature <br> control section $\left[{ }^{\circ} \mathrm{C}\right]$ | Current <br> $[\mathrm{A}]$ |
| :---: | :---: | :---: | :---: |
| $07: 05$ | 19,6 | 19,6 | 38 |
| $07: 21$ | 37 | 32 | 36 |
| $07: 29$ | 41 | 35 | 35,6 |
| $07: 36$ | 44 | 37 | 35,2 |
| $07: 45$ | 48 | 40 | 34,8 |
| $07: 53$ | 50 | 42 | 34,4 |
| $08: 01$ | 52 | 44 | 34,2 |
| $08: 07$ | 53 | 45 | 34,2 |
| $08: 13$ | 55 | 46 | 34 |

## Absorber Temperature <br> $34^{\circ} \mathrm{C}$

## Full power test with a HTS 80-12-UF switch

| For this Measurement we have a pulser with three switches HTS 80-12 UF. |  |
| :--- | :--- |
| Full power test with three Switches 1000 single pulses and $1 \mu \mathrm{~s}$ spacing |  |
| each. |  |
|  |  |
| Voltages | 6.5 kV |
| Current | 78.5 A |
| Pulse length | 16 ns |
| Rise time (10-90\%) | 4 ns |
| Micro pulse repetition rate | 3 MHz |
| Macro pulse repetition rate | $1 \mathrm{~Hz} / 5 \mathrm{~Hz}$ |
| Number of pulse | 3000 |



Absorber Temperature $45^{\circ} \mathrm{C}$
Absorber Temperature $105^{\circ} \mathrm{C}$


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## Measurement at KEK ATF Ring

The beam kick is observed by a turn-by turn BPM as the amplitude of the oscillation of the betatron frequency.
The kick effect is measured by scanning the pulse timing for the beam timing.


Timing Scan(DESY Behlke HTS-80-12-UF)


Next steps:
New Behlke switches with a water cooling and with selected Mosfet semiconductor are ordered (delivery date 08/05).
Investigate the pulse to pulse stability and the long-term stability
(temperature drift) of a 3 MHz pulser.

## XFEL activities



Next steps:

- New Behlke switches with a rep. rate of 5 MHz (delivery date unknown) are under development at the company. We expect a rectangular current pulse.
- The alternative: a pulser with 5 parallel HTS 80-12 UF switches.
- Or use a pulser with single semiconductors (Directed Energy, Inc. DE-150 102N02A). Pulse form: a sinus half-wave.

For this beam distribution we need a 5 MHz pulser with following data:

|  |  | XFEL |
| :--- | :--- | :--- |
| Energy | GeV | 20 |
| Deflection angle | mrad | 0,3 |
| Rep. Rate <br> Macro pulse | Hz | 10 |
| Rep. Rate <br> Bunch | MHz | 5 |
| Pulse Width | ns | 200 |
| Bdl | mTm | 12 |
| Accuracy | $5 \mathrm{e}-5$ |  |
| Ripple | $5 \mathrm{e}-5$ |  |
| Bunch spacing | ns | 200 |
| Pulse structure |  | burst |
| Amplitude |  | variable |

## XFEL activities



- principle set up of the pulser
- Directed Energy, Inc. Mosfet DE-150 102N02A
- Generate single pulses with 200ns spacing



## XFEL activities



For this beam distribution we need a long pulse modulator with following data:

|  |  | XFEL |
| :--- | :--- | :--- |
| Energy | GeV | 20 |
| Deflection angle | mrad | 0,3 |
| Rep. Rate <br> Macro pulse | Hz | 10 |
| Rep. Rate <br> Bunch | MHz | 5 |
| Pulse Width | $\mu \mathrm{s}$ | 290 |
| Bdl | mTm | 12 |
| Accuracy | $5 \mathrm{e}-5$ |  |
| Ripple | $5 \mathrm{e}-5$ |  |
| Total length | m | 10 |
| Gap height | mm | $10-50$ |
| Bunch spacing | ns | 200 |

